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Secondary electron emission from MgO thin film as the protective layer of ac-PDP

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Low-energy ion induced secondary electron emission from MgO thin film adopted currently as the protecting layer of ac-PDP was characterized for five noble ions with kinetic energies ranging from 50eV to 225 eV. The secondary electron emission values obtained by a pulsed ion method decreased monotonically as the ions become heavier and also the kinetic energy gets smaller given the ions.

The secondary electron emission coefficients from MgO layer were fitted by an empirical, which will be discussed briefly.